

DEVICE  
SPECIFICATION

## SONET/SDH/ATM CLOCK RECOVERY UNIT

S3024

## FEATURES

- Complies with Bellcore and ITU-T specifications for jitter tolerance, jitter transfer and jitter generation
- On-chip high frequency PLL with internal loop filter for clock recovery
- Supports clock recovery for OC-12/STM-4 (622.08 Mbit/s) or OC-3/STM-1 (155.52 Mbit/s) NRZ data
- 19.44 MHz reference frequency
- Lock detect—monitors frequency
- 264 mW typical power dissipation
- Low-jitter LVPECL interface
- Maintains downstream clock in absence of data inputs
- 3.3V supply
- Available in a 20 pin TSSOP package
- Active High LVPECL Signal Detect

## GENERAL DESCRIPTION

The function of the S3024 clock recovery unit is to derive high speed timing signals for SONET/SDH-based equipment. The S3024 is implemented using AMCC's proven Phase Locked Loop (PLL) technology.

The S3024 receives either an OC-12/STM-4 or OC-3/STM-1 scrambled NRZ signal and recovers the clock from the data. The chip outputs a differential LVPECL bit clock and retimed data. Figure 1 shows a typical network application.

The S3024 utilizes an on-chip PLL which consists of a phase detector, a loop filter, and a Voltage Controlled Oscillator (VCO). The phase detector compares the phase relationship between the VCO output and the serial data input. A loop filter converts the phase detector output into a smooth DC voltage, and the DC voltage is input to the VCO whose frequency is varied by this voltage. A block diagram is shown in Figure 2.

Figure 1. System Block Diagram

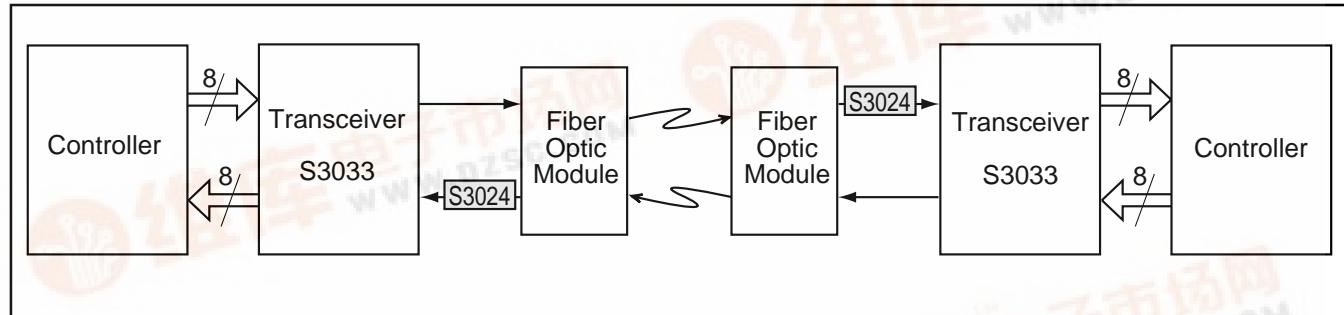
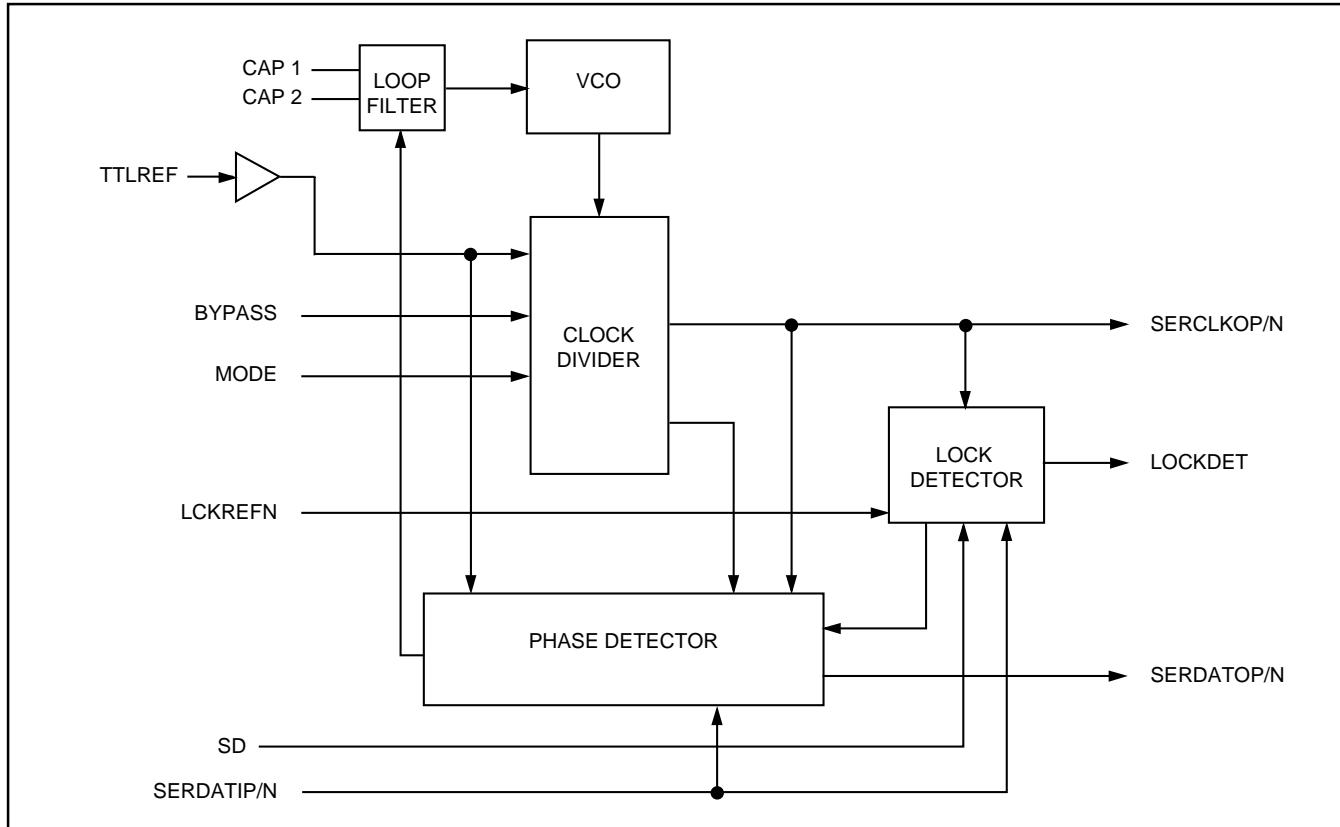


Figure 2. Functional Block Diagram



## OVERVIEW

The S3024 supports clock recovery for the OC-12/STM-4 or OC-3/STM-1 data rates. Differential serial data is input to the chip at the specified rate and clock recovery is performed on the incoming data stream. A reference clock is required to minimize the PLL lock time and provide a stable output clock source in the absence of serial input data. Retimed data and clock are output from the S3024.

## JITTER CHARACTERISTICS

### Performance

The S3024 PLL complies with the jitter specifications proposed for SONET/SDH equipment defined by the T1X1.6/91-022 document, when used with differential inputs and outputs as shown in Figure 3.

### Jitter Transfer

The jitter transfer function is defined as the ratio of jitter on the output OC-N/STS-N signal to the jitter applied on the input OC-N/STS-N signal versus frequency. Jitter transfer requirements are shown in Figure 5. The measurement condition is that input sinusoidal jitter up to the mask level in Figure 4 be applied for each of the OC-N/STS-N rates.

### Input Jitter Tolerance

Input jitter tolerance is defined as the peak to peak amplitude of sinusoidal jitter applied on the input signal that causes an equivalent 1 dB optical/electrical power penalty. SONET input jitter tolerance requirements are shown in Figure 4. The measurement condition is the input jitter amplitude which causes an equivalent of 1 dB power penalty.

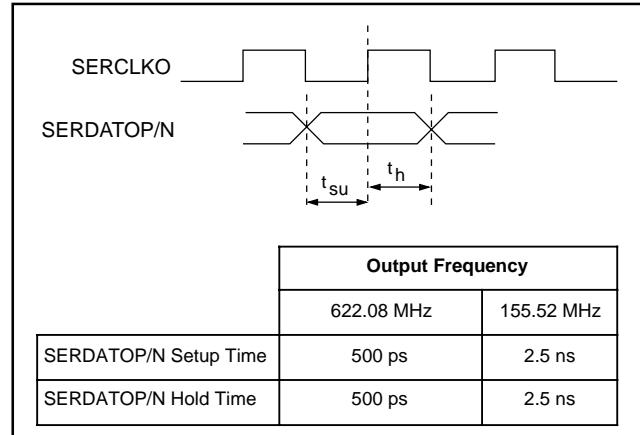
### Serial Data Output Set-up and Hold Time

The output set-up and hold times are represented by the waveforms shown in Figure 3.

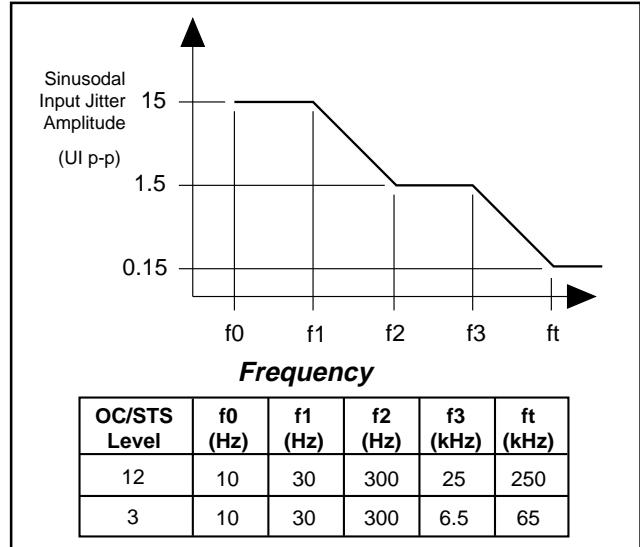
### Jitter Generation

The jitter generation of the serial clock and serial data outputs shall not exceed the value specified in Table 6 when a serial data input with less than 14ps (OC-12) or 56ps (OC-3) rms jitter is presented to the serial data inputs.

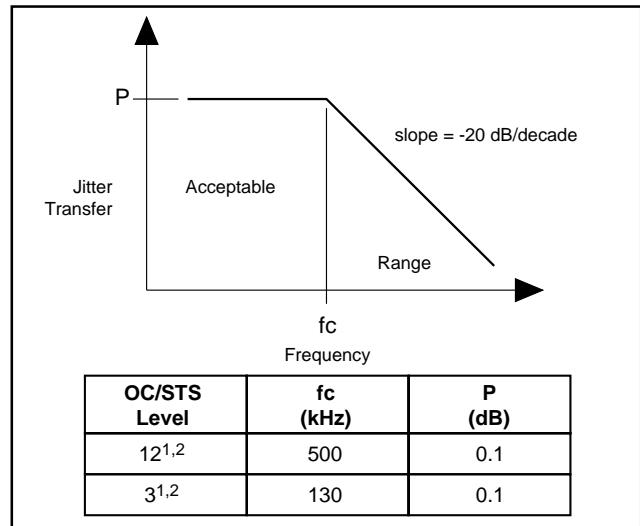
**Figure 3. Clock Output to Data Transition Delay**



**Figure 4. Input Jitter Tolerance Specification**



**Figure 5. Jitter Transfer Specification**



1. Bellcore Specifications: TR-NWT-000253, Issue 2, December 1991.

2. CCITT Recommendations: G.958.

**Table 1. S3024 Pin Assignment and Descriptions**

Pin Name	Level	I/O	Pin #	Description
SERDATIP SERDATIN	Diff. LVPECL	I	2 3	Serial Data In. A clock is recovered from transitions on these inputs.
BYPASS	LVTTL	I	16	Bypass enable, active High. Used during production test to bypass the VCO in the PLL. Tie to ground for normal operation.
SD	LVPECL	I	15	Signal Detect, active High. A single-ended 10K PECL input to be driven by the external optical receiver module to indicate presence of received optical power. When SD is inactive, the PLL will be forced to lock to the TTLREF input and the SERDATOP/N output will be held in the logic Low state. When SD is active, data on the SERDATIP/N pins will be processed normally.
TTLREF	LVTTL	I	7	TTL Reference clock input used to establish the initial operating frequency of the clock recovery PLL, and also used as a standby clock in the absence of data or when LOCKDET is inactive.
CAP1 CAP2	—	I	18 17	External Loop Filter Pins. The loop filter capacitor and resistors are connected to these pins. The capacitor value should be 1.0 $\mu$ F $\pm$ 10% tolerance, X7R dielectric. 50 V is recommended. The resistor values are 82 $\Omega$ $\pm$ 5%. See Figure 8.
LCKREFN	LVTTL	I	8	Lock to Reference, active Low. When active, the serial clock output will be forced to lock to the TTLREF local reference input and the SERDATOP/N output will be held at the logic low state. See Table 2.
MODE	LVTTL	I	6	Rate select used to select the bit rate of the device. Set High to select 622.08 Mbit/s. Set Low to select 155.52 Mbit/s.
SERDATOP SERDATON	Diff. LVPECL	O	14 13	Serial Data Out signal that is the delayed version of the incoming data stream (SERDATI). Updated on the falling edge of Serial Clock Out (SERCLKOP).
SERCLKOP SERCLKON	Diff. LVPECL	O	12 11	Serial Clock Out signal that is phase aligned with Serial Data Out (SERDATOP/N). (See Figure 3.)

Table 1. S3024 Pin Assignment and Descriptions (Continued)

Pin Name	Level	I/O	Pin #	Description
LOCKDET	LVPECL	O	5	<p>Lock Detect, active High. When active, this output indicates that the PLL is locked to the serial data inputs, and valid clock and data are present at the serial outputs. When inactive, it indicates that the PLL is locked to the local reference clock. The lock detect will go inactive under the following conditions:</p> <ol style="list-style-type: none"> <li>1. If SD is inactive.</li> <li>2. If the VCO drifts away from the local reference clock by more than 1000 ppm.</li> <li>3. If LCKREFN is active.</li> </ol> <p>Lock detect will return to the active state if the serial clock is within 250 ppm of the reference clock frequency.</p>
DGND	GND	—	9	Digital Ground (0V)
DVCC	+3.3V	—	10	Digital Power Supply (+3.3V)
AGND	GND	—	4, 19	Analog Ground (0V)
AVCC	+3.3V	—	1, 20	Analog Power Supply (+3.3V)

Figure 6. S3024 Pinout

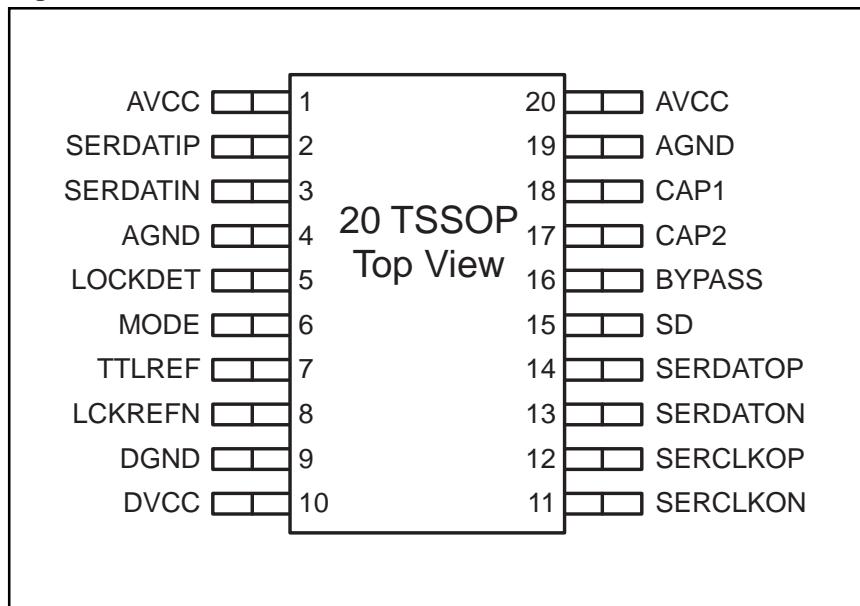


Figure 7. S3024A TSSOP Package

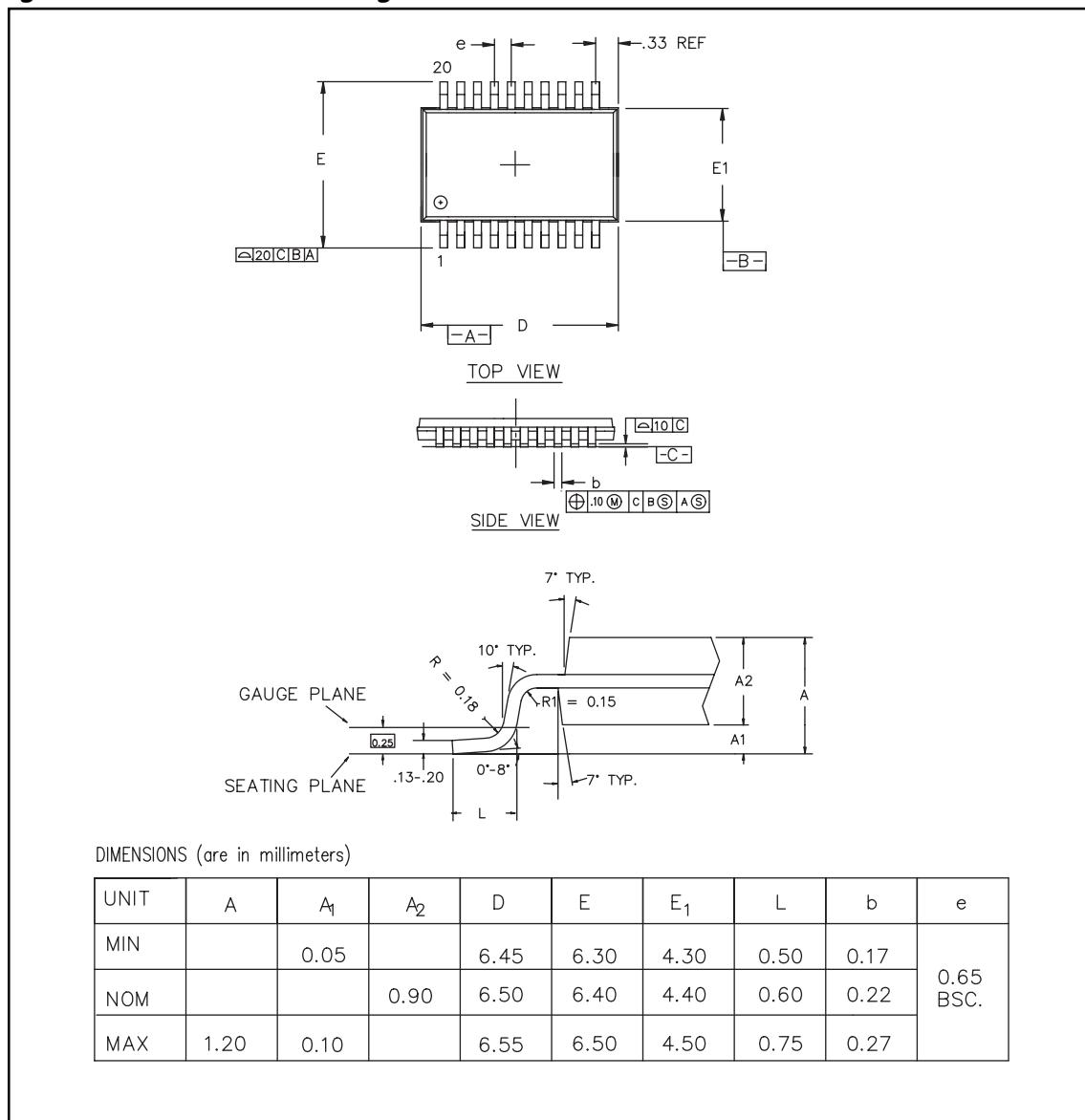


Table 2. Clock and Data Output Control

SD	LCKREFN	LOCK DETECT	SERCLKOP/N	SERDATP/N
X	X	0	Active	0
X	0	0	Active	0
0	X	0	Active	0
1	1	1	Active	Active

Table 3. Thermal Management

Max Power	$\Theta_{ja}$ (Still Air)
347 mW	77° C/W

**Table 4. Absolute Maximum Ratings**

Parameter	Min	Typ	Max	Unit
Storage Temperature	-65		+150	° C
Voltage on $V_{CC}$ with Respect to GND	-0.5		+7.0	V
Voltage on any LVTTL Input Pin	-0.5		$V_{CC}$	V
Voltage on any LVPECL Input Pin	$V_{CC}$ -2.0		$V_{CC}$	V
LVTTL Output Sink Current			20	mA
LVTTL Output Source Current			10	mA
High Speed LVPECL Output Source Current			50	mA

**ESD Ratings**

The S3024 is rated to the following ESD voltages based on the human body model:

1. All pins are rated at or above 1500 V except pin 17, pin 18, and pin 20.

**Table 5. Recommended Operating Conditions**

Parameter	Min	Typ	Max	Unit
Ambient Temperature under Bias (Industrial)	-40		+85	° C
Ambient Temperature under Bias (Commercial)	0		+70	° C
Voltage on $V_{CC}$ with Respect to GND	3.135	3.3	3.465	V
Voltage on any LVTTL Input Pin	0.0		$V_{CC}$	V
Voltage on any LVPECL Input Pin	$V_{CC}$ -2		$V_{CC}$	V
PECL Output Source Current (50Ω to $V_{CC}$ -2V)		14	25	mA
ICC Supply Current		80	100	mA

**Table 6. Performance Specifications**

Parameter	Min	Typ	Max	Units	Condition
Nominal VCO Center Frequency		622.08		MHz	
Reference Clock Frequency Tolerance Clock Recovery <sup>1</sup>	-250		+250	ppm	
OC-12/STS-12 Capture Range		±500		ppm	With respect to fixed reference frequency
Clock Output Duty Cycle	45		55	% of UI	Minimum transition density of 20%
Acquisition Lock Time <sup>1</sup> OC-12/STS-12			16	μsec	With device already powered up and valid REFCLK.
PECL Output Rise & Fall Times			600	ps	10% to 90%, 50Ω to -2V equivalent load, 5 pF cap
SERCLKOP/N Jitter Generation		0.005	0.01	UI	With less than 14ps rms jitter on SERDATIP/N data inputs
OC-12/STS-12 Jitter Tolerance <sup>1</sup>	0.5			UI	Sinusoidal input jitter. Amplitude on SERDATIP/N data inputs from 12 kHz to 5 MHz.

1. Guaranteed but not tested.

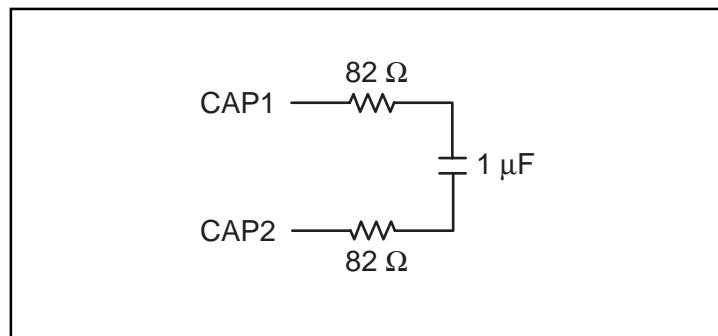
**Table 7. LVTTI Input/Output DC Characteristics<sup>1</sup>**(T<sub>A</sub> = -40°C to +85°C, V<sub>CC</sub> = 3.3 V ±5%)

Symbol	Parameter	Min	Typ	Max	Unit	Test Conditions
V <sub>IL</sub> <sup>1</sup>	Input LOW Voltage			0.8	V	Guaranteed Input LOW Voltage for all inputs
V <sub>IH</sub> <sup>1</sup>	Input HIGH Voltage	2.0			V	Guaranteed Input HIGH Voltage for all inputs
I <sub>IL</sub>	Input LOW Current	-400.0			µA	V <sub>CC</sub> = MAX, V <sub>IN</sub> = 0.5V
I <sub>IH</sub>	Input HIGH Current			50.0	µA	V <sub>CC</sub> = MAX, V <sub>IN</sub> = 2.7V
I <sub>I</sub>	Input HIGH Current at Max V <sub>IN</sub>			1.0	mA	V <sub>CC</sub> = MAX, V <sub>IN</sub> = V <sub>CC</sub>
V <sub>IK</sub>	Input Clamp Diode Voltage	-1.2			V	V <sub>CC</sub> = MIN, I <sub>IN</sub> = -18.0mA

1. These input levels provide a zero-noise immunity and should only be tested in a static, noise-free environment.

**Table 8. LVPECL Input/Output DC Characteristics**(T<sub>A</sub> = -40°C to +85°C, V<sub>CC</sub> = 3.3 V)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
V <sub>IL</sub>	Input Low Voltage	V <sub>CC</sub> -2.000		V <sub>CC</sub> -1.441	V	Guaranteed Input Low Voltage for single-ended inputs
V <sub>IH</sub>	Input High Voltage	V <sub>CC</sub> -1.225		V <sub>CC</sub> -0.570	V	Guaranteed Input High Voltage for single-ended inputs
V <sub>IL</sub>	Input Low Voltage	V <sub>CC</sub> -2.000		V <sub>CC</sub> -0.700	V	Guaranteed Input Low Voltage for differential inputs
V <sub>IH</sub>	Input High Voltage	V <sub>CC</sub> -1.750		V <sub>CC</sub> -0.450	V	Guaranteed Input High Voltage for differential inputs
V <sub>ID</sub>	Input Differential Voltage	0.250	0.500	1.400	V	Differential Input Voltage
I <sub>IH</sub>	Input High Current	-0.500		100	µA	V <sub>ID</sub> = 500mV
I <sub>IL</sub>	Input Low Current	-0.60		20.000	µA	V <sub>ID</sub> = 500mV
V <sub>OL</sub>	Output Low Voltage	V <sub>CC</sub> -2.000		V <sub>CC</sub> -1.57	V	50Ω Termination to V <sub>CC</sub> -2V
V <sub>OH</sub>	Output High Voltage	V <sub>CC</sub> -1.35		V <sub>CC</sub> -0.670	V	50Ω Termination to V <sub>CC</sub> -2V
V <sub>OD</sub>	Output Differential Voltage	0.390		1.330	V	Differential Output Voltage

**Figure 8. Loop Filter Connections**

***Ordering Information***

PREFIX	DEVICE	PACKAGE
S – Integrated Circuit	3024	A – 20 TSSOP

X      XXXX      X  
Prefix      Device      Package

ISO 9001  
CERTIFIED

**Applied Micro Circuits Corporation • 6290 Sequence Dr., San Diego, CA 92121**

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